

S/N 09/834751

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Sergey A. Velichko et al.

Examiner: Craig Steven Miller

Serial No.: 09/834751

Group Art Unit: 2812

Filed: April 13, 2001

Docket: 303.750US1

Title: CONCURRENT CONTROL OF SEMICONDUCTOR PARAMETRIC TESTING

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

In compliance with the duty imposed by 37 C.F.R. § 1.56, and in accordance with 37 C.F.R. §§ 1.97 *et. seq.*, the enclosed materials are brought to the attention of the Examiner for consideration in connection with the above-identified patent application. Applicants respectfully request that this Information Disclosure Statement be entered and the documents listed on the attached Form 1449 be considered by the Examiner and made of record. Pursuant to the provisions of MPEP 609, Applicants request that a copy of the 1449 form, initialed as being considered by the Examiner, be returned to the Applicants with the next official communication.

Pursuant to 37 C.F.R. §1.97(c)(2), Applicants have included the fee of \$180.00 as set forth in 37 C.F.R. §1.17(p). Please charge any additional fees or credit any overpayment to Deposit Account No. 19-0743.

The Examiner is invited to contact the Applicants' Representative at the below-listed telephone number if there are any questions regarding this communication.

Respectfully submitted,

SERGEY A. VELICHKO ET AL.

By their Representatives,

SCHWEGMAN, LUNDBERG, WOESSNER & KLOTH, P.A.  
P.O. Box 2938  
Minneapolis, MN 55402  
(612) 349-9581

Date

Jan 28 '04

By

[Signature]

John M. Dahl

Reg. No. 44,639

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 28th day of January, 2004.

Name

Amy Moravsky

Signature

[Signature]

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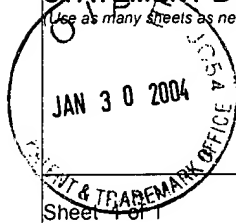
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Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)



Complete if Known

**Application Number** 09/834751  
**Filing Date** April 13, 2001  
**First Named Inventor** Velichko, Sergey  
**Group Art Unit** 2812  
**Examiner Name** Miller, Craig

**Attorney Docket No:** 303.750US1

US PATENT DOCUMENTS						
Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Class	Subclass	Filing Date If Appropriate
	US20030028343	02/06/2003	Velichko, Sergey A., et al.	702	122	04/25/2002
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	US-5,241,266	08/31/1993	Ahmad, A. , et al.	714	733	04/10/1992
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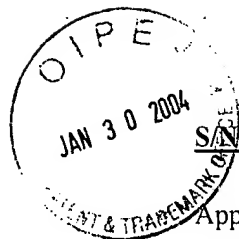
OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
		BLUNN, R G., "Concurrent fault tolerant control of semiconductor measurement and testing", 2001 IEEE International Semiconductor Manufacturing Symposium, (October 8-10, 2001),455-458	

EXAMINER

DATE CONSIDERED

Substitute Disclosure Statement Form (PTO-1449)

\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. <sup>1</sup> Applicant's unique citation designation number (optional) <sup>2</sup> Applicant is to place a check mark here if English language Translation is attached



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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Sergey A. Velichko et al. Examiner: Craig S. Miller  
Serial No.: 09/834751 Group Art Unit: 2812  
Filed: April 13, 2001 Docket: 303.750US1  
Title: CONCURRENT CONTROL OF SEMICONDUCTOR PARAMETRIC TESTING

COMMUNICATION CONCERNING RELATED APPLICATION(S)

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Applicants would like to bring to the Examiner's attention the following related application(s) in the above-identified patent application:

<u>Serial/Patent No.</u>	<u>Filing Date</u>	<u>Attorney Docket</u>	<u>Title</u>
10/131934	April 25, 2002	303.771US1	INTELLIGENT MEASUREMENT MODULAR SEMICONDUCTOR PARAMETRIC TEST SYSTEM
10/133685	April 25, 2002	303.821US1	DYNAMICALLY ADAPTABLE SEMICONDUCTOR PARAMETRIC TESTING
10/417640	April 17, 2003	303.855US1	DYNAMIC CREATION AND MODIFICATION OF WAFER TEST MAPS DURING WAFER TESTING

Respectfully submitted,

SERGEY A. VELICHKO ET AL.

By Applicants' Representatives,

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Minneapolis, MN 55402  
(612) 349-9581

Date

Jan 28 04

By

John M. Dahl

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Reg. No. 44,639

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Name

Amy Moriarty

Signature

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